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# Understanding <u>Embedded - FPGAs (Field Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1600
Number of Logic Elements/Cells	3800
Total RAM Bits	51200
Number of I/O	256
Number of Gates	44000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	304-BFQFP Exposed Pad
Supplier Device Package	304-PQFP (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc4044xl-1hq304i

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



# **Detailed Functional Description**

XC4000 Series devices achieve high speed through advanced semiconductor technology and improved architecture. The XC4000E and XC4000X support system clock rates of up to 80 MHz and internal performance in excess of 150 MHz. Compared to older Xilinx FPGA families, XC4000 Series devices are more powerful. They offer on-chip edge-triggered and dual-port RAM, clock enables on I/O flip-flops, and wide-input decoders. They are more versatile in many applications, especially those involving RAM. Design cycles are faster due to a combination of increased routing resources and more sophisticated software.

#### **Basic Building Blocks**

Xilinx user-programmable gate arrays include two major configurable elements: configurable logic blocks (CLBs) and input/output blocks (IOBs).

- CLBs provide the functional elements for constructing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.

Three other types of circuits are also available:

- 3-State buffers (TBUFs) driving horizontal longlines are associated with each CLB.
- Wide edge decoders are available around the periphery of each device.
- An on-chip oscillator is provided.

Programmable interconnect resources provide routing paths to connect the inputs and outputs of these configurable elements to the appropriate networks.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA. Each of these available circuits is described in this section.

### **Configurable Logic Blocks (CLBs)**

Configurable Logic Blocks implement most of the logic in an FPGA. The principal CLB elements are shown in Figure 1. Two 4-input function generators (F and G) offer unrestricted versatility. Most combinatorial logic functions need four or fewer inputs. However, a third function generator (H) is provided. The H function generator has three inputs. Either zero, one, or two of these inputs can be the outputs of F and G; the other input(s) are from outside the CLB. The CLB can, therefore, implement certain functions of up to nine variables, like parity check or expandable-identity comparison of two sets of four inputs.

Each CLB contains two storage elements that can be used to store the function generator outputs. However, the storage elements and function generators can also be used independently. These storage elements can be configured as flip-flops in both XC4000E and XC4000X devices; in the XC4000X they can optionally be configured as latches. DIN can be used as a direct input to either of the two storage elements. H1 can drive the other through the H function generator. Function generator outputs can also drive two outputs independent of the storage element outputs. This versatility increases logic capacity and simplifies routing.

Thirteen CLB inputs and four CLB outputs provide access to the function generators and storage elements. These inputs and outputs connect to the programmable interconnect resources outside the block.

#### **Function Generators**

Four independent inputs are provided to each of two function generators (F1 - F4 and G1 - G4). These function generators, with outputs labeled F' and G', are each capable of implementing any arbitrarily defined Boolean function of four inputs. The function generators are implemented as memory look-up tables. The propagation delay is therefore independent of the function implemented.

A third function generator, labeled H', can implement any Boolean function of its three inputs. Two of these inputs can optionally be the F' and G' functional generator outputs. Alternatively, one or both of these inputs can come from outside the CLB (H2, H0). The third input must come from outside the block (H1).

Signals from the function generators can exit the CLB on two outputs. F' or H' can be connected to the X output. G' or H' can be connected to the Y output.

A CLB can be used to implement any of the following functions:

- any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables<sup>1</sup>
- any single function of five variables
- any function of four variables together with some functions of six variables
- · some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

<sup>1.</sup> When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.



#### Set/Reset

An asynchronous storage element input (SR) can be configured as either set or reset. This configuration option determines the state in which each flip-flop becomes operational after configuration. It also determines the effect of a Global Set/Reset pulse during normal operation, and the effect of a pulse on the SR pin of the CLB. All three set/reset functions for any single flip-flop are controlled by the same configuration data bit.

The set/reset state can be independently specified for each flip-flop. This input can also be independently disabled for either flip-flop.

The set/reset state is specified by using the INIT attribute, or by placing the appropriate set or reset flip-flop library symbol.

SR is active High. It is not invertible within the CLB.

#### Global Set/Reset

A separate Global Set/Reset line (not shown in Figure 1) sets or clears each storage element during power-up, re-configuration, or when a dedicated Reset net is driven active. This global net (GSR) does not compete with other routing resources; it uses a dedicated distribution network.

Each flip-flop is configured as either globally set or reset in the same way that the local set/reset (SR) is specified. Therefore, if a flip-flop is set by SR, it is also set by GSR. Similarly, a reset flip-flop is reset by both SR and GSR.



Figure 2: Schematic Symbols for Global Set/Reset

GSR can be driven from any user-programmable pin as a global reset input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GSR pin of the STARTUP symbol. (See Figure 2.) A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global Set/Reset signal.

Alternatively, GSR can be driven from any internal node.

#### Data Inputs and Outputs

The source of a storage element data input is programmable. It is driven by any of the functions F', G', and H', or by the Direct In (DIN) block input. The flip-flops or latches drive the XQ and YQ CLB outputs.

Two fast feed-through paths are available, as shown in Figure 1. A two-to-one multiplexer on each of the XQ and YQ outputs selects between a storage element output and any of the control inputs. This bypass is sometimes used by the automated router to repower internal signals.

#### **Control Signals**

Multiplexers in the CLB map the four control inputs (C1 - C4 in Figure 1) into the four internal control signals (H1, DIN/H2, SR/H0, and EC). Any of these inputs can drive any of the four internal control signals.

When the logic function is enabled, the four inputs are:

- EC Enable Clock
- SR/H0 Asynchronous Set/Reset or H function generator Input 0
- DIN/H2 Direct In or H function generator Input 2
- H1 H function generator Input 1.

When the memory function is enabled, the four inputs are:

- EC Enable Clock
- WE Write Enable
- D0 Data Input to F and/or G function generator
- D1 Data input to G function generator (16x1 and 16x2 modes) or 5th Address bit (32x1 mode).

#### Using FPGA Flip-Flops and Latches

The abundance of flip-flops in the XC4000 Series invites pipelined designs. This is a powerful way of increasing performance by breaking the function into smaller subfunctions and executing them in parallel, passing on the results through pipeline flip-flops. This method should be seriously considered wherever throughput is more important than latency.

To include a CLB flip-flop, place the appropriate library symbol. For example, FDCE is a D-type flip-flop with clock enable and asynchronous clear. The corresponding latch symbol (for the XC4000X only) is called LDCE.

In XC4000 Series devices, the flip flops can be used as registers or shift registers without blocking the function generators from performing a different, perhaps unrelated task. This ability increases the functional capacity of the devices.

The CLB setup time is specified between the function generator inputs and the clock input K. Therefore, the specified CLB flip-flop setup time includes the delay through the function generator.

#### Using Function Generators as RAM

Optional modes for each CLB make the memory look-up tables in the F' and G' function generators usable as an array of Read/Write memory cells. Available modes are level-sensitive (similar to the XC4000/A/H families), edge-triggered, and dual-port edge-triggered. Depending on the selected mode, a single CLB can be configured as either a 16x2, 32x1, or 16x1 bit array.





Figure 7: 16x1 Edge-Triggered Dual-Port RAM

Figure 8 shows the write timing for level-sensitive, single-port RAM.

The relationships between CLB pins and RAM inputs and outputs for single-port level-sensitive mode are shown in Table 7.

Figure 9 and Figure 10 show block diagrams of a CLB configured as 16x2 and 32x1 level-sensitive, single-port RAM.

#### Initializing RAM at Configuration

Both RAM and ROM implementations of the XC4000 Series devices are initialized during configuration. The initial contents are defined via an INIT attribute or property

attached to the RAM or ROM symbol, as described in the schematic library guide. If not defined, all RAM contents are initialized to all zeros, by default.

RAM initialization occurs only during configuration. The RAM content is not affected by Global Set/Reset.

**Table 7: Single-Port Level-Sensitive RAM Signals** 

RAM Signal	CLB Pin	Function
D	D0 or D1	Data In
A[3:0]	F1-F4 or G1-G4	Address
WE	WE	Write Enable
0	F' or G'	Data Out



Figure 8: Level-Sensitive RAM Write Timing

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Figure 14: Detail of XC4000E Dedicated Carry Logic

### Input/Output Blocks (IOBs)

User-configurable input/output blocks (IOBs) provide the interface between external package pins and the internal logic. Each IOB controls one package pin and can be configured for input, output, or bidirectional signals.

Figure 15 shows a simplified block diagram of the XC4000E IOB. A more complete diagram which includes the boundary scan logic of the XC4000E IOB can be found in Figure 40 on page 43, in the "Boundary Scan" section.

The XC4000X IOB contains some special features not included in the XC4000E IOB. These features are highlighted in a simplified block diagram found in Figure 16, and discussed throughout this section. When XC4000X special features are discussed, they are clearly identified in the text. Any feature not so identified is present in both XC4000E and XC4000X devices.

#### IOB Input Signals

Two paths, labeled I1 and I2 in Figure 15 and Figure 16, bring input signals into the array. Inputs also connect to an input register that can be programmed as either an edge-triggered flip-flop or a level-sensitive latch.

The choice is made by placing the appropriate library symbol. For example, IFD is the basic input flip-flop (rising edge triggered), and ILD is the basic input latch (transparent-High). Variations with inverted clocks are available, and some combinations of latches and flip-flops can be implemented in a single IOB, as described in the *XACT Libraries Guide*.

The XC4000E inputs can be globally configured for either TTL (1.2V) or 5.0 volt CMOS thresholds, using an option in the bitstream generation software. There is a slight input hysteresis of about 300mV. The XC4000E output levels are also configurable; the two global adjustments of input threshold and output level are independent.

Inputs on the XC4000XL are TTL compatible and 3.3V CMOS compatible. Outputs on the XC4000XL are pulled to the 3.3V positive supply.

The inputs of XC4000 Series 5-Volt devices can be driven by the outputs of any 3.3-Volt device, if the 5-Volt inputs are in TTL mode.

Supported sources for XC4000 Series device inputs are shown in Table 8.

Table 8: Supported Sources for XC4000 Series Device Inputs

		0E/EX Inputs	XC4000XL Series Inputs
Source	5 V, TTL	5 V, CMOS	3.3 V CMOS
Any device, Vcc = 3.3 V, CMOS outputs	V	Unreli	√
XC4000 Series, Vcc = 5 V, TTL outputs	V	-able Data	√
Any device, $Vcc = 5 \text{ V}$ , TTL outputs $(Voh \le 3.7 \text{ V})$	√	Data	√
Any device, Vcc = 5 V, CMOS outputs	V	√	√

#### XC4000XL 5-Volt Tolerant I/Os

The I/Os on the XC4000XL are fully 5-volt tolerant even though the  $V_{\rm CC}$  is 3.3 volts. This allows 5 V signals to directly connect to the XC4000XL inputs without damage, as shown in Table 8. In addition, the 3.3 volt  $V_{\rm CC}$  can be applied before or after 5 volt signals are applied to the I/Os. This makes the XC4000XL immune to power supply sequencing problems.

#### **Registered Inputs**

The I1 and I2 signals that exit the block can each carry either the direct or registered input signal.

The input and output storage elements in each IOB have a common clock enable input, which, through configuration, can be activated individually for the input or output flip-flop, or both. This clock enable operates exactly like the EC pin on the XC4000 Series CLB. It cannot be inverted within the IOB.

The storage element behavior is shown in Table 9.

Table 9: Input Register Functionality (active rising edge is shown)

Mode	Clock	Clock Enable	D	Q
Power-Up or GSR	X	X	Х	SR
Flip-Flop		1*	D	D
	0	Х	Х	Q
Latch	1	1*	Х	Q
	0	1*	D	D
Both	Χ	0	Х	Q

Legend:

X Don't care
Rising edge

SR Set or Reset value. Reset is default.

0\* Input is Low or unconnected (default value)
1\* Input is High or unconnected (default value)

#### **Optional Delay Guarantees Zero Hold Time**

The data input to the register can optionally be delayed by several nanoseconds. With the delay enabled, the setup time of the input flip-flop is increased so that normal clock routing does not result in a positive hold-time requirement. A positive hold time requirement can lead to unreliable, temperature- or processing-dependent operation.

The input flip-flop setup time is defined between the data measured at the device I/O pin and the clock input at the IOB (not at the clock pin). Any routing delay from the device clock pin to the clock input of the IOB must, therefore, be subtracted from this setup time to arrive at the real setup time requirement relative to the device pins. A short specified setup time might, therefore, result in a negative setup time at the device pins, i.e., a positive hold-time requirement.

When a delay is inserted on the data line, more clock delay can be tolerated without causing a positive hold-time requirement. Sufficient delay eliminates the possibility of a data hold-time requirement at the external pin. The maximum delay is therefore inserted as the default.

The XC4000E IOB has a one-tap delay element: either the delay is inserted (default), or it is not. The delay guarantees a zero hold time with respect to clocks routed through any of the XC4000E global clock buffers. (See "Global Nets and Buffers (XC4000E only)" on page 35 for a description of the global clock buffers in the XC4000E.) For a shorter input register setup time, with non-zero hold, attach a NODELAY attribute or property to the flip-flop.

The XC4000X IOB has a two-tap delay element, with choices of a full delay, a partial delay, or no delay. The attributes or properties used to select the desired delay are shown in Table 10. The choices are no added attribute, MEDDELAY, and NODELAY. The default setting, with no added attribute, ensures no hold time with respect to any of the XC4000X clock buffers, including the Global Low-Skew buffers. MEDDELAY ensures no hold time with respect to the Global Early buffers. Inputs with NODELAY may have a positive hold time with respect to all clock buffers. For a description of each of these buffers, see "Global Nets and Buffers (XC4000X only)" on page 37.

Table 10: XC4000X IOB Input Delay Element

Value	When to Use
full delay	Zero Hold with respect to Global
(default, no	Low-Skew Buffer, Global Early Buffer
attribute added)	
MEDDELAY	Zero Hold with respect to Global Early
	Buffer
NODELAY	Short Setup, positive Hold time



Any XC4000 Series 5-Volt device with its outputs configured in TTL mode can drive the inputs of any typical 3.3-Volt device. (For a detailed discussion of how to interface between 5 V and 3.3 V devices, see the 3V Products section of *The Programmable Logic Data Book*.)

Supported destinations for XC4000 Series device outputs are shown in Table 12.

An output can be configured as open-drain (open-collector) by placing an OBUFT symbol in a schematic or HDL code, then tying the 3-state pin (T) to the output signal, and the input pin (I) to Ground. (See Figure 18.)

Table 12: Supported Destinations for XC4000 Series Outputs

	ХС	ries i	
Destination	3.3 V, CMOS	5 V, TTL	5 V, CMOS
Any typical device, Vcc = 3.3 V,	<b>V</b>	V	some <sup>1</sup>
CMOS-threshold inputs			
Any device, Vcc = 5 V,	V V		√
TTL-threshold inputs			
Any device, Vcc = 5 V,	Unre	liable	√
CMOS-threshold inputs	Data		

1. Only if destination device has 5-V tolerant inputs



Figure 18: Open-Drain Output

#### **Output Slew Rate**

The slew rate of each output buffer is, by default, reduced, to minimize power bus transients when switching non-critical signals. For critical signals, attach a FAST attribute or property to the output buffer or flip-flop.

For XC4000E devices, maximum total capacitive load for simultaneous fast mode switching in the same direction is 200 pF for all package pins between each Power/Ground pin pair. For XC4000X devices, additional internal

Power/Ground pin pairs are connected to special Power and Ground planes within the packages, to reduce ground bounce. Therefore, the maximum total capacitive load is 300 pF between each external Power/Ground pin pair. Maximum loading may vary for the low-voltage devices.

For slew-rate limited outputs this total is two times larger for each device type: 400 pF for XC4000E devices and 600 pF for XC4000X devices. This maximum capacitive load should not be exceeded, as it can result in ground bounce of greater than 1.5 V amplitude and more than 5 ns duration. This level of ground bounce may cause undesired transient behavior on an output, or in the internal logic. This restriction is common to all high-speed digital ICs, and is not particular to Xilinx or the XC4000 Series.

XC4000 Series devices have a feature called "Soft Start-up," designed to reduce ground bounce when all outputs are turned on simultaneously at the end of configuration. When the configuration process is finished and the device starts up, the first activation of the outputs is automatically slew-rate limited. Immediately following the initial activation of the I/O, the slew rate of the individual outputs is determined by the individual configuration option for each IOB.

#### **Global Three-State**

A separate Global 3-State line (not shown in Figure 15 or Figure 16) forces all FPGA outputs to the high-impedance state, unless boundary scan is enabled and is executing an EXTEST instruction. This global net (GTS) does not compete with other routing resources; it uses a dedicated distribution network.

GTS can be driven from any user-programmable pin as a global 3-state input. To use this global net, place an input pad and input buffer in the schematic or HDL code, driving the GTS pin of the STARTUP symbol. A specific pin location can be assigned to this input using a LOC attribute or property, just as with any other user-programmable pad. An inverter can optionally be inserted after the input buffer to invert the sense of the Global 3-State signal. Using GTS is similar to GSR. See Figure 2 on page 11 for details.

Alternatively, GTS can be driven from any internal node.



# Output Multiplexer/2-Input Function Generator (XC4000X only)

As shown in Figure 16 on page 21, the output path in the XC4000X IOB contains an additional multiplexer not available in the XC4000E IOB. The multiplexer can also be configured as a 2-input function generator, implementing a pass-gate, AND-gate, OR-gate, or XOR-gate, with 0, 1, or 2 inverted inputs. The logic used to implement these functions is shown in the upper gray area of Figure 16.

When configured as a multiplexer, this feature allows two output signals to time-share the same output pad; effectively doubling the number of device outputs without requiring a larger, more expensive package.

When the MUX is configured as a 2-input function generator, logic can be implemented within the IOB itself. Combined with a Global Early buffer, this arrangement allows very high-speed gating of a single signal. For example, a wide decoder can be implemented in CLBs, and its output gated with a Read or Write Strobe Driven by a BUFGE buffer, as shown in Figure 19. The critical-path pin-to-pin delay of this circuit is less than 6 nanoseconds.

As shown in Figure 16, the IOB input pins Out, Output Clock, and Clock Enable have different delays and different flexibilities regarding polarity. Additionally, Output Clock sources are more limited than the other inputs. Therefore, the Xilinx software does not move logic into the IOB function generators unless explicitly directed to do so.

The user can specify that the IOB function generator be used, by placing special library symbols beginning with the letter "O." For example, a 2-input AND-gate in the IOB function generator is called OAND2. Use the symbol input pin labelled "F" for the signal on the critical path. This signal is placed on the OK pin — the IOB input with the shortest delay to the function generator. Two examples are shown in Figure 20.



Figure 19: Fast Pin-to-Pin Path in XC4000X



Figure 20: AND & MUX Symbols in XC4000X IOB

#### Other IOB Options

There are a number of other programmable options in the XC4000 Series IOB.

#### Pull-up and Pull-down Resistors

Programmable pull-up and pull-down resistors are useful for tying unused pins to Vcc or Ground to minimize power consumption and reduce noise sensitivity. The configurable pull-up resistor is a p-channel transistor that pulls to Vcc. The configurable pull-down resistor is an n-channel transistor that pulls to Ground.

The value of these resistors is 50 k $\Omega$  – 100 k $\Omega$ . This high value makes them unsuitable as wired-AND pull-up resistors.

The pull-up resistors for most user-programmable IOBs are active during the configuration process. See Table 22 on page 58 for a list of pins with pull-ups active before and during configuration.

After configuration, voltage levels of unused pads, bonded or un-bonded, must be valid logic levels, to reduce noise sensitivity and avoid excess current. Therefore, by default, unused pads are configured with the internal pull-up resistor active. Alternatively, they can be individually configured with the pull-down resistor, or as a driven output, or to be driven by an external source. To activate the internal pull-up, attach the PULLUP library component to the net attached to the pad. To activate the internal pull-down, attach the PULLDOWN library component to the net attached to the pad.

#### Independent Clocks

Separate clock signals are provided for the input and output flip-flops. The clock can be independently inverted for each flip-flop within the IOB, generating either falling-edge or rising-edge triggered flip-flops. The clock inputs for each IOB are independent, except that in the XC4000X, the Fast Capture latch shares an IOB input with the output clock pin.

#### Early Clock for IOBs (XC4000X only)

Special early clocks are available for IOBs. These clocks are sourced by the same sources as the Global Low-Skew buffers, but are separately buffered. They have fewer loads and therefore less delay. The early clock can drive either the IOB output clock or the IOB input clock, or both. The early clock allows fast capture of input data, and fast clock-to-output on output data. The Global Early buffers that drive these clocks are described in "Global Nets and Buffers (XC4000X only)" on page 37.

#### **Global Set/Reset**

As with the CLB registers, the Global Set/Reset signal (GSR) can be used to set or clear the input and output registers, depending on the value of the INIT attribute or property. The two flip-flops can be individually configured to set

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or clear on reset and after configuration. Other than the global GSR net, no user-controlled set/reset signal is available to the I/O flip-flops. The choice of set or clear applies to both the initial state of the flip-flop and the response to the Global Set/Reset pulse. See "Global Set/Reset" on page 11 for a description of how to use GSR.

#### **JTAG Support**

Embedded logic attached to the IOBs contains test structures compatible with IEEE Standard 1149.1 for boundary scan testing, permitting easy chip and board-level testing. More information is provided in "Boundary Scan" on page 42.

#### **Three-State Buffers**

A pair of 3-state buffers is associated with each CLB in the array. (See Figure 27 on page 30.) These 3-state buffers can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources. Programmable pull-up resistors attached to these longlines help to implement a wide wired-AND function.

The buffer enable is an active-High 3-state (i.e. an active-Low enable), as shown in Table 13.

Another 3-state buffer with similar access is located near each I/O block along the right and left edges of the array. (See Figure 33 on page 34.)

The horizontal longlines driven by the 3-state buffers have a weak keeper at each end. This circuit prevents undefined floating levels. However, it is overridden by any driver, even a pull-up resistor.

Special longlines running along the perimeter of the array can be used to wire-AND signals coming from nearby IOBs or from internal longlines. These longlines form the wide edge decoders discussed in "Wide Edge Decoders" on page 27.

#### Three-State Buffer Modes

The 3-state buffers can be configured in three modes:

- · Standard 3-state buffer
- Wired-AND with input on the I pin
- Wired OR-AND

#### Standard 3-State Buffer

All three pins are used. Place the library element BUFT. Connect the input to the I pin and the output to the O pin. The T pin is an active-High 3-state (i.e. an active-Low enable). Tie the T pin to Ground to implement a standard buffer.

#### Wired-AND with Input on the I Pin

The buffer can be used as a Wired-AND. Use the WAND1 library symbol, which is essentially an open-drain buffer. WAND4, WAND8, and WAND16 are also available. See the *XACT Libraries Guide* for further information.

The T pin is internally tied to the I pin. Connect the input to the I pin and the output to the O pin. Connect the outputs of all the WAND1s together and attach a PULLUP symbol.

#### Wired OR-AND

The buffer can be configured as a Wired OR-AND. A High level on either input turns off the output. Use the WOR2AND library symbol, which is essentially an open-drain 2-input OR gate. The two input pins are functionally equivalent. Attach the two inputs to the I0 and I1 pins and tie the output to the O pin. Tie the outputs of all the WOR2ANDs together and attach a PULLUP symbol.

#### Three-State Buffer Examples

Figure 21 shows how to use the 3-state buffers to implement a wired-AND function. When all the buffer inputs are High, the pull-up resistor(s) provide the High output.

Figure 22 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active-High 3-state (T) is identical to an active-Low output enable, as shown in Table 13.

**Table 13: Three-State Buffer Functionality** 

IN	Т	OUT
X	1	Z
IN	0	IN



Figure 21: Open-Drain Buffers Implement a Wired-AND Function



Figure 41 on page 44 is a diagram of the XC4000 Series boundary scan logic. It includes three bits of Data Register per IOB, the IEEE 1149.1 Test Access Port controller, and the Instruction Register with decodes.

XC4000 Series devices can also be configured through the boundary scan logic. See "Readback" on page 55.

#### **Data Registers**

The primary data register is the boundary scan register. For each IOB pin in the FPGA, bonded or not, it includes three bits for In, Out and 3-State Control. Non-IOB pins have appropriate partial bit population for In or Out only. PROGRAM, CCLK and DONE are not included in the boundary scan register. Each EXTEST CAPTURE-DR state captures all In, Out, and 3-state pins.

The data register also includes the following non-pin bits: TDO.T, and TDO.O, which are always bits 0 and 1 of the

data register, respectively, and BSCANT.UPD, which is always the last bit of the data register. These three boundary scan bits are special-purpose Xilinx test signals.

The other standard data register is the single flip-flop BYPASS register. It synchronizes data being passed through the FPGA to the next downstream boundary scan device.

The FPGA provides two additional data registers that can be specified using the BSCAN macro. The FPGA provides two user pins (BSCAN.SEL1 and BSCAN.SEL2) which are the decodes of two user instructions. For these instructions, two corresponding pins (BSCAN.TDO1 and BSCAN.TDO2) allow user scan data to be shifted out on TDO. The data register clock (BSCAN.DRCK) is available for control of test logic which the user may wish to implement with CLBs. The NAND of TCK and RUN-TEST-IDLE is also provided (BSCAN.IDLE).



Figure 40: Block Diagram of XC4000E IOB with Boundary Scan (some details not shown). XC4000X Boundary Scan Logic is Identical.



Figure 41: XC4000 Series Boundary Scan Logic

#### **Instruction Set**

The XC4000 Series boundary scan instruction set also includes instructions to configure the device and read back the configuration data. The instruction set is coded as shown in Table 17.

#### **Bit Sequence**

The bit sequence within each IOB is: In, Out, 3-State. The input-only M0 and M2 mode pins contribute only the In bit to the boundary scan I/O data register, while the output-only M1 pin contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in XDE or Epic), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 42. The device-specific pinout tables for the XC4000 Series include the boundary scan locations for each IOB pin.

BSDL (Boundary Scan Description Language) files for XC4000 Series devices are available on the Xilinx FTP site.

#### **Including Boundary Scan in a Schematic**

If boundary scan is only to be used during configuration, no special schematic elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 43.

Even if the boundary scan symbol is used in a schematic, the input pins TMS, TCK, and TDI can still be used as inputs to be routed to internal logic. Care must be taken not to force the chip into an undesired boundary scan state by inadvertently applying boundary scan input patterns to these pins. The simplest way to prevent this is to keep TMS High, and then apply whatever signal is desired to TDI and TCK.



#### **Setting CCLK Frequency**

For Master modes, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for XC4000E and XC4000EX devices and from 0.6 MHz to 1.8 MHz for XC4000XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for XC4000E/EX devices and from 5 MHz to 15 MHz for XC4000XL devices. The frequency is selected by an option when running the bitstream generation software. If an XC4000 Series Master is driving an XC3000- or XC2000-family slave, slow CCLK mode must be used. In addition, an XC4000XL device driving a XC4000E or XC4000EX should use slow mode. Slow mode is the default

Table 19: XC4000 Series Data Stream Formats

Data Type	All Other Modes (D0)
Fill Byte	11111111b
Preamble Code	0010b
Length Count	COUNT(23:0)
Fill Bits	1111b
Start Field	Ob
Data Frame	DATA(n-1:0)
CRC or Constant	xxxx (CRC)
Field Check	or 0110b
Extend Write Cycle	_
Postamble	01111111b
Start-Up Bytes	xxh
Legend:	
Not shaded	Once per bitstream
Light	Once per data frame
Dark	Once per device

#### **Data Stream Format**

The data stream ("bitstream") format is identical for all configuration modes.

The data stream formats are shown in Table 19. Bit-serial data is read from left to right, and byte-parallel data is effectively assembled from this serial bitstream, with the first bit in each byte assigned to D0.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones. This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 20 and Table 21). Each frame begins with a start field and ends with an error check. A postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional startup bytes to shift the last data through the chain. All startup bytes are don't-cares; these bytes are not included in bitstreams created by the Xilinx software.

A selection of CRC or non-CRC error checking is allowed by the bitstream generation software. The non-CRC error checking tests for a designated end-of-frame field for each frame. For CRC error checking, the software calculates a running CRC and inserts a unique four-bit partial check at the end of each frame. The 11-bit CRC check of the last frame of an FPGA includes the last seven data bits.

Detection of an error results in the suspension of data loading and the pulling down of the  $\overline{\text{INIT}}$  pin. In Master modes, CCLK and address signals continue to operate externally. The user must detect  $\overline{\text{INIT}}$  and initialize a new configuration by pulsing the  $\overline{\text{PROGRAM}}$  pin Low or cycling Vcc.





Figure 48: Start-up Logic

#### Readback

The user can read back the content of configuration memory and the level of certain internal nodes without interfering with the normal operation of the device.

Readback not only reports the downloaded configuration bits, but can also include the present state of the device, represented by the content of all flip-flops and latches in CLBs and IOBs, as well as the content of function generators used as RAMs.

Note that in XC4000 Series devices, configuration data is *not* inverted with respect to configuration as it is in XC2000 and XC3000 families.

XC4000 Series Readback does not use any dedicated pins, but uses four internal nets (RDBK.TRIG, RDBK.DATA, RDBK.RIP and RDBK.CLK) that can be routed to any IOB. To access the internal Readback signals, place the READ-

BACK library symbol and attach the appropriate pad symbols, as shown in Figure 49.

After Readback has been initiated by a High level on RDBK.TRIG after configuration, the RDBK.RIP (Read In Progress) output goes High on the next rising edge of RDBK.CLK. Subsequent rising edges of this clock shift out Readback data on the RDBK.DATA net.

Readback data does not include the preamble, but starts with five dummy bits (all High) followed by the Start bit (Low) of the first frame. The first two data bits of the first frame are always High.

Each frame ends with four error check bits. They are read back as High. The last seven bits of the last frame are also read back as High. An additional Start bit (Low) and an 11-bit Cyclic Redundancy Check (CRC) signature follow, before RDBK.RIP returns Low.



**Table 22: Pin Functions During Configuration** 

CONFIGURATION MODE <m2:m1:m0></m2:m1:m0>							
SLAVE SERIAL <1:1:1>	MASTER SERIAL <0:0:0>	SYNCH. PERIPHERAL <0:1:1>	ASYNCH. PERIPHERAL <1:0:1>	MASTER PARALLEL DOWN <1:1:0>	MASTER PARALLEL UP <1:0:0>	USER OPERATION	
M2(HIGH) (I)	M2(LOW) (I)	M2(LOW) (I)	M2(HIGH) (I)	M2(HIGH) (I)	M2(HIGH) (I)	(I)	
M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	(O)	
M0(HIGH) (I)	M0(LOW) (I)	M0(HIGH) (I)	M0(HIGH) (I)	M0(LOW) (I)	M0(LOW) (I)	(I)	
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O	
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O	
ĪNIT	ĪNIT	ĪNIT	ĪNIT	ĪNIT	ĪNIT	I/O	
DONE	DONE	DONE	DONE	DONE	DONE	DONE	
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM	
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (O)	CCLK (O)	CCLK (O)	CCLK (I)	
		RDY/BUSY (O)	RDY/BUSY (O)	RCLK (O)	RCLK (O)	I/O	
			RS (I)			I/O	
			CSO (I)			I/O	
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O	
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O	
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O	
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O	
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O	
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	I/O	
		DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	I/O	
DIN (I)	DIN (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	I/O	
DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	SGCK4-GCK6-I/O	
TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O	
TCK	TCK	TCK	TCK	TCK	TCK	TCK-I/O	
TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O	
TDO	TDO	TDO	TDO	TDO	TDO	TDO-(O)	
			WS (I)	A0	A0	I/O	
				A1	A1	PGCK4-GCK7-I/O	
			CS1	A2	A2	I/O	
				A3	A3	I/O	
				A4	A4	I/O	
				A5	A5	I/O	
				A6	A6	I/O	
				A7	A7	I/O	
				A8	A8	I/O	
				A9	A9	I/O	
				A10	A10	I/O	
				A11	A11	I/O	
				A12	A12	I/O	
				A13	A13	I/O	
				A14	A14	I/O	
				A15	A15	SGCK1-GCK8-I/O	
				A16	A16	PGCK1-GCK1-I/O	
				A17	A17	I/O	
				A18*	A18*	I/O	
				A19*	A19*	I/O	
				A20*	A20*	I/O	
				A21*	A21*	I/O	
						ALL OTHERS	



**Table 23: Pin Functions During Configuration** 

SLAVE SERIAL <1:1:1>	MASTER SERIAL <0:0:0>	SYNCH. PERIPHERAL <0:1:1>	ASYNCH. PERIPHERAL <1:0:1>	MASTER PARALLEL DOWN <1:1:0>	MASTER PARALLEL UP <1:0:0>	USER OPERATION
M2(HIGH) (I)	M2(LOW) (I)	M2(LOW) (I)	M2(HIGH) (I)	M2(HIGH) (I)	M2(HIGH) (I)	(I)
M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	M1(HIGH) (I)	M1(LOW) (I)	(O)
M0(HIGH) (I)	M0(LOW) (I)	M0(HIGH) (I)	M0(HIGH) (I)	M0(LOW) (I)	M0(LOW) (I)	(I)
HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	HDC (HIGH)	I/O
LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	LDC (LOW)	I/O
ĪNIT	ĪNIT	ĪNĪT	ĪNIT	ĪNIT	ĪNIT	I/O
DONE	DONE	DONE	DONE	DONE	DONE	DONE
PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM (I)	PROGRAM
CCLK (I)	CCLK (O)	CCLK (I)	CCLK (O)	CCLK (O)	CCLK (O)	CCLK (I)
		RDY/BUSY (O)	RDY/BUSY (O)	RCLK (O)	RCLK (O)	I/O
			RS (I)			I/O
			CSO (I)			I/O
		DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	DATA 7 (I)	I/O
		DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	DATA 6 (I)	I/O
		DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	DATA 5 (I)	I/O
		DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	DATA 4 (I)	I/O
		DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	DATA 3 (I)	I/O
		DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	DATA 2 (I)	I/O
		DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	DATA 1 (I)	I/O
DIN (I)	DIN (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	DATA 0 (I)	I/O
DOUT	DOUT	DOUT	DOUT	DOUT	DOUT	SGCK4-GCK6-I/O
TDI	TDI	TDI	TDI	TDI	TDI	TDI-I/O
TCK	TCK	TCK	TCK	TCK	TCK	TCK-I/O
TMS	TMS	TMS	TMS	TMS	TMS	TMS-I/O
TDO	TDO	TDO	TDO	TDO	TDO	TDO-(O)
			WS (I)	A0	A0	I/O
				A1	A1	PGCK4-GCK7-I/O
			CS1	A2	A2	I/O
				A3	A3	I/O
				A4	A4	I/O
				A5	A5	I/O
				A6	A6	I/O
				A7	A7	I/O
				A8	A8	I/O
				A9	A9	I/O
				A10	A10	I/O
				A11	A11	I/O
				A12	A12	I/O
				A13	A13	I/O
				A14	A14	I/O
				A15	A15	SGCK1-GCK8-I/O
				A16	A16	PGCK1-GCK1-I/O
				A17	A17	I/O
				A18*	A18*	I/O
				A19*	A19*	I/O
				A20*	A20*	I/O
				A21*	A21*	I/O
						ALL OTHERS

<sup>\*</sup> XC4000X only

Notes 1. A shaded table cell represents a 50 k $\Omega$  - 100 k $\Omega$  pull-up before and during configuration.

 <sup>(</sup>I) represents an input; (O) represents an output.
 INIT is an open-drain output during configuration.



# **Configuration Timing**

The seven configuration modes are discussed in detail in this section. Timing specifications are included.

#### **Slave Serial Mode**

In Slave Serial mode, an external signal drives the CCLK input of the FPGA. The serial configuration bitstream must be available at the DIN input of the lead FPGA a short setup time before each rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin.

There is an internal delay of 0.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

Figure 51 shows a full master/slave system. An XC4000 Series device in Slave Serial mode should be connected as shown in the third device from the left.

Slave Serial mode is selected by a <111> on the mode pins (M2, M1, M0). Slave Serial is the default mode if the mode pins are left unconnected, as they have weak pull-up resistors during configuration.



Figure 51: Master/Slave Serial Mode Circuit Diagram



	Description		Symbol	Min	Max	Units
	DIN setup	1	T <sub>DCC</sub>	20		ns
	DIN hold	2	T <sub>CCD</sub>	0		ns
CCLK	DIN to DOUT	3	T <sub>CCO</sub>		30	ns
CCLK	High time	4	T <sub>CCH</sub>	45		ns
	Low time	5	T <sub>CCL</sub>	45		ns
	Frequency		F <sub>CC</sub>		10	MHz

Note: Configuration must be delayed until the INIT pins of all daisy-chained FPGAs are High.

Figure 52: Slave Serial Mode Programming Switching Characteristics



#### Master Serial Mode

In Master Serial mode, the CCLK output of the lead FPGA drives a Xilinx Serial PROM that feeds the FPGA DIN input. Each rising edge of the CCLK output increments the Serial PROM internal address counter. The next data bit is put on the SPROM data output, connected to the FPGA DIN pin. The lead FPGA accepts this data on the subsequent rising CCLK edge.

The lead FPGA then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal pipeline delay of 1.5 CCLK periods, which means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

In the bitstream generation software, the user can specify Fast ConfigRate, which, starting several bits into the first frame, increases the CCLK frequency by a factor of eight.

For actual timing values please refer to "Configuration Switching Characteristics" on page 68. Be sure that the serial PROM and slaves are fast enough to support this data rate. XC2000, XC3000/A, and XC3100A devices do not support the Fast ConfigRate option.

The SPROM CE input can be driven from either LDC or DONE. Using LDC avoids potential contention on the DIN pin, if this pin is configured as user-I/O, but LDC is then restricted to be a permanently High user output after configuration. Using DONE can also avoid contention on DIN, provided the early DONE option is invoked.

Figure 51 on page 60 shows a full master/slave system. The leftmost device is in Master Serial mode.

Master Serial mode is selected by a <000> on the mode pins (M2, M1, M0).



	Description	,	Symbol	Min	Max	Units
CCLK	DIN setup	1	T <sub>DSCK</sub>	20		ns
COLIN	DIN hold	2	T <sub>CKDS</sub>	0		ns

Notes: 1. At power-up, Vcc must rise from 2.0 V to Vcc min in less than 25 ms, otherwise delay configuration by pulling PROGRAM Low until Vcc is valid.

2. Master Serial mode timing is based on testing in slave mode.

Figure 53: Master Serial Mode Programming Switching Characteristics



#### **Master Parallel Modes**

In the two Master Parallel modes, the lead FPGA directly addresses an industry-standard byte-wide EPROM, and accepts eight data bits just before incrementing or decrementing the address outputs.

The eight data bits are serialized in the lead FPGA, which then presents the preamble data—and all data that overflows the lead device—on its DOUT pin. There is an internal delay of 1.5 CCLK periods, after the rising CCLK edge that accepts a byte of data (and also changes the EPROM address) until the falling CCLK edge that makes the LSB (D0) of this byte appear at DOUT. This means that DOUT changes on the falling CCLK edge, and the next FPGA in the daisy chain accepts data on the subsequent rising CCLK edge.

The PROM address pins can be incremented or decremented, depending on the mode pin settings. This option allows the FPGA to share the PROM with a wide variety of microprocessors and micro controllers. Some processors must boot from the bottom of memory (all zeros) while others must boot from the top. The FPGA is flexible and can load its configuration bitstream from either end of the memory.

Master Parallel Up mode is selected by a <100> on the mode pins (M2, M1, M0). The EPROM addresses start at 00000 and increment.

Master Parallel Down mode is selected by a <110> on the mode pins. The EPROM addresses start at 3FFFF and decrement.

#### Additional Address lines in XC4000 devices

The XC4000X devices have additional address lines (A18-A21) allowing the additional address space required to daisy-chain several large devices.

The extra address lines are programmable in XC4000EX devices. By default these address lines are not activated. In the default mode, the devices are compatible with existing XC4000 and XC4000E products. If desired, the extra address lines can be used by specifying the address lines option in bitgen as 22 (bitgen -g AddressLines:22). The lines (A18-A21) are driven when a master device detects, via the bitstream, that it should be using all 22 address lines. Because these pins will initially be pulled high by internal pull-ups, designers using Master Parallel Up mode should use external pull down resistors on pins A18-A21. If Master Parallel Down mode is used external resistors are not necessary.

All 22 address lines are always active in Master Parallel modes with XC4000XL devices. The additional address lines behave identically to the lower order address lines. If the Address Lines option in bitgen is set to 18, it will be ignored by the XC4000XL device.

The additional address lines (A18-A21) are not available in the PC84 package.



Figure 54: Master Parallel Mode Circuit Diagram





	Description	,	Symbol	Min	Max	Units
Write	Effective Write time (CSO, WS=Low; RS, CS1=High)	1	T <sub>CA</sub>	100		ns
	DIN setup time	2	T <sub>DC</sub>	60		ns
	DIN hold time	3	T <sub>CD</sub>	0		ns
RDY	RDY/BUSY delay after end of Write or Read	4	T <sub>WTRB</sub>		60	ns
	RDY/BUSY active after beginning of Read	7			60	ns
	RDY/BUSY Low output (Note 4)	6	T <sub>BUSY</sub>	2	9	CCLK periods

- Notes: 1. Configuration must be delayed until the NIT pins of all daisy-chained FPGAs are High.
  - 2. The time from the end of WS to CCLK cycle for the new byte of data depends on the completion of previous byte processing and the phase of the internal timing generator for CCLK.
  - 3. CCLK and DOUT timing is tested in slave mode.
  - 4. T<sub>RUSY</sub> indicates that the double-buffered parallel-to-serial converter is not yet ready to receive new data. The shortest T<sub>BUSY</sub> occurs when a byte is loaded into an empty parallel-to-serial converter. The longest T<sub>BUSY</sub> occurs when a new word is loaded into the input register before the second-level buffer has started shifting out data

This timing diagram shows very relaxed requirements. Data need not be held beyond the rising edge of WS. RDY/BUSY will go active within 60 ns after the end of WS. A new write may be asserted immediately after RDY/BUSY goes Low, but write may not be terminated until RDY/BUSY has been High for one CCLK period.

Figure 59: Asynchronous Peripheral Mode Programming Switching Characteristics



# **Configuration Switching Characteristics**



## Master Modes (XC4000E/EX)

Description		Symbol	Min	Max	Units	
	M0 = High	T <sub>POR</sub>	10	40	ms	
Power-On Reset	M0 = Low	T <sub>POR</sub>	40	130	ms	
Program Latency	T <sub>Pl</sub>	30	200	μs per		
					CLB column	
CCLK (output) Delay		T <sub>ICCK</sub>	40	250	μs	
CCLK (output) Period, slow		T <sub>CCLK</sub>	640	2000	ns	
CCLK (output) Period, fast		T <sub>CCLK</sub>	80	250	ns	

# Master Modes (XC4000XL)

Description		Symbol	Min	Max	Units
	M0 = High	T <sub>POR</sub>	10	40	ms
Power-On Reset	M0 = Low	T <sub>POR</sub>	40	130	ms
Program Latency		T <sub>Pl</sub>	30	200	μs per
					CLB column
CCLK (output) Delay		T <sub>ICCK</sub>	40	250	μs
CCLK (output) Period, slow		T <sub>CCLK</sub>	540	1600	ns
CCLK (output) Period, fast		T <sub>CCLK</sub>	67	200	ns

# Slave and Peripheral Modes (All)

Description	Symbol	Min	Max	Units
Power-On Reset	T <sub>POR</sub>	10	33	ms
Program Latency	T <sub>Pl</sub>	30	200	μs per CLB column
CCLK (input) Delay (required)	T <sub>ICCK</sub>	4		μs
CCLK (input) Period (required)	T <sub>CCLK</sub>	100		ns

# Product Obsolete or Under Obsolescence XC4000E and XC4000X Series Field Programmable Gate Arrays



Table 25: Component Availability Chart for XC4000E FPGAs

F	PINS	84	100	100	120	144	156	160	191	208	208	223	225	240	240	299	304
TYPE		Plast. PLCC	Plast. PQFP	Plast. VQFP	Ceram. PGA	Plast. TQFP	Ceram. PGA	Plast. PQFP	Ceram. PGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	Plast. BGA	High-Perf. QFP	Plast. PQFP	Ceram. PGA	High-Perf. QF
CODE		PC84	PQ100	VQ100	PG120	TQ144	PG156	PQ160	PG191	HQ208	PQ208	PG223	BG225	HQ240	PQ240	PG299	HQ304 High-Perf.
	-4	CI	CI	CI	CI												
XC4003E	-3	СІ	СІ	СІ	СІ												
AC4003E	-2	CI	СІ	СІ	CI												
	-1	С	С	С	С												
	-4	СІ	СІ			СІ	СІ	CI			CI						
XC4005E	-3	СІ	СІ			СІ	СІ	СІ			СІ						
AC4005E	-2	CI	СІ			СІ	СІ	СІ			СІ						
İ	-1	С	С			С	С	С			С						
	-4	CI				CI	СІ	СІ			CI						
XC4006E	-3	СІ				CI	СІ	СІ			CI						
AC4000E	-2	CI				CI	CI	CI			CI						
Ī	-1	С				С	С	С			С						
	-4	СІ						CI	CI		CI						
XC4008E	-3	СІ						СІ	CI		CI						
AC4000L	-2	CI						CI	CI		CI						
	-1	С						С	С		С						
	-4	CI						CI	CI	CI	CI		CI				
XC4010E	-3	CI						CI	CI	CI	CI		CI				
AC4010L	-2	CI						CI	CI	CI	CI		CI				
	-1	С						С	С	С	С		С				
	-4							CI		CI	CI	CI	CI	CI	CI		
XC4013E	-3							CI		CI	CI	CI	CI	CI	CI		
NO-1010L	-2							CI		CI	CI	CI	CI	CI	CI		
	-1							С		С	С	С	С	С	С		
	-4									CI		CI		CI			
XC4020E	-3									CI		CI		CI			
7.0-020L	-2									CI		CI		CI			
	-1									С		С		С			
	-4											CI		CI		CI	CI
XC4025E	-3											CI		CI		CI	CI
1/29/99	-2											С		С		С	С

C = Commercial  $T_J = 0^{\circ}$  to +85°C I= Industrial  $T_J = -40^{\circ}$ C to +100°C

Table 26: Component Availability Chart for XC4000EX FPGAs

PINS		208	240	299	304	352	411	432
TYPE		High-Perf. QFP	High-Perf. QFP	Ceram. PGA	High-Perf. QFP	Plast. BGA	Ceram. PGA	Plast. BGA
CODE		HQ208	HQ240	PG299	HQ304	BG352	PG411	BG432
	-4	CI	CI	CI	CI	CI		
XC4028EX	-3	CI	CI	CI	CI	CI		
	-2	С	С	С	С	С		
	-4		CI		CI	CI	CI	CI
XC4036EX	-3		CI		CI	CI	CI	CI
	-2		С		С	С	С	С

1/29/99

C = Commercial  $T_J = 0^{\circ}$  to +85°C I= Industrial  $T_J = -40^{\circ}$ C to +100°C